



N-channel Enhancement Mode Power MOSFET

芯天下技术股份有限公司

XTX Technology Inc.

Tel: (+86 755) 28229862 Fax: (+86 755) 28229847

Web Site: http://www.xtxtech.com/ Technical Contact: fae@xtxtech.com

* Information furnished is believed to be accurate and reliable. However, XTX Technology Inc. assumes no responsibility for the consequences of use of such information or for any infringement of patents of other rights of third parties which may result from its use. No license is granted by implication or otherwise under any patent rights of XTX Technology Inc. Specifications mentioned in this publication are subjected to change without notice. This publication supersedes and replaces all information previously supplied. XTX Technology Inc. products are not authorized for use as critical components in life support devices or systems without express written approval of XTX Technology Inc. The XTX logo is a registered trademark of XTX Technology Inc. All other names are the property of their respective own.



FEATURES

♦ 40V, 100A

 $R_{DS(ON)}\!<2.9m\Omega\ @\ VGS=10V$

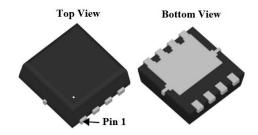
 $R_{DS(ON)}\!<\!4.5m\Omega\ \ @VGS=4.5V$

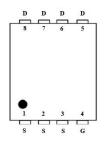
- ◆ Advanced Trench Technology
- ◆ Excellent R_{DS(ON)} and Low Gate Charge
- ◆ Lead Free

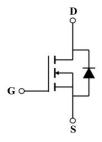


- ◆ Load Switch
- ◆ PWM Application
- ◆ Power Management









PDFN5*6-8L

Pin Assignment

Schematic Diagram

PACKAGE MARKING AND ORDERING INFORMATION

OPN	Package	Quantity
BRT40N100P2	PDFN5*6-8L	5000pcs/Reel

ABSOLUTE MAXIMUM RATINGS

Symbol	Definition		Ratings	Unit
V_{DS}	Drain-to-Source Voltage		40	V
$V_{ m GS}$	Gate-to-Source Voltage		±20	V
I	Continuous Drain Current	$T_{\rm C} = 25^{\circ}{\rm C}$	100	A
I _D Continuous E	Continuous Drain Current	$T_C = 100$ °C	63	A
I_{DM}	Pulsed Drain Current (1)		400	A
E _{AS}	Single Pulsed Avalanche Energy (2)		306	mJ
P _D	Power Dissipation, $T_C = 25^{\circ}C$		125	W
$R_{ heta m JC}$	Thermal Resistance, Junction to Case		1.0	°C/W
T _J , T _{STG}	Junction & Storage Temperature Range		-55 ~ +150	°C



$\textbf{ELECTRICAL CHARACTERISTICS} \hspace{0.1cm} \textbf{(All test condition is } T_J\!\!=\!\!25^{\circ}\text{C} \text{, unless otherwise noted)}$

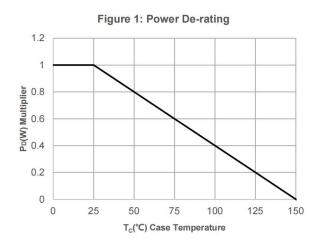
Symbol	Parameter	Condition	Min	Тур	Max	Unit	
Off Characteristics							
V _{(BR)DSS}	Drain-Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	40	-	-	V	
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=40V,V_{GS}=0V$	-	-	1	uA	
I_{GSS}	Gate-Body Leakage Current	$V_{DS} = 0V, V_{GS} = \pm 20V$	-	-	±100	nA	
On Characte	On Characteristics						
V _{GS(TH)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250uA$	1.0	1.5	2.5	V	
D	Statis Design Common ON Resignation (3)	$V_{GS} = 10V, I_D = 30A$		2.4	2.9	mΩ	
R _{DS(ON)}	Static Drain-Source ON-Resistance ⁽³⁾	$V_{GS} = 4.5V, I_D = 20A$		3.0	4.5	mΩ	
Dynamic Ch	aracteristics		1				
Ciss	Input Capacitance		4376	6152	8270	pF	
Coss	Output Capacitance	$V_{GS} = 0V, V_{DS} = 20V,$ f = 1MHz	358	487	677	pF	
C_{rss}	Reverse Transfer Capacitance		249	313	470	pF	
$R_{\rm g}$	Gate Resistance	f=1MHz	-	1.4	-	Ω	
Qg	Total Gate Charge		79	111	150	nC	
Q_{gs}	Gate Source Charge	$V_{GS} = 0 \text{ to } 10V$ $V_{DS} = 20V, I_D = 30A$	14	20	27	nC	
Q_{gd}	Gate Drain("Miller") Charge		15	23	28	nC	
Switching Cl	haracteristics						
t _{d(on)}	Turn-On Delay Time		-	14	-	ns	
$t_{\rm r}$	Turn-On Rise Time	$V_{GS} = 10V, V_{DD} = 19.5V$	-	28	-	ns	
$t_{ m d(off)}$	Turn-Off Delay Time	$I_D=30A$, $R_{GEN}=3\Omega$	-	77	-	ns	
t_{f}	Turn-Off Fall Time		-	23	-	ns	
Drain-Sourc	e Diode Characteristics	1	1	1	1	1	
Is	Continuous Source Current		-	-	100	A	
$ m V_{SD}$	Forward on voltage	$V_{GS} = 0V, I_S = 30A$	-	-	1.2	V	
Trr	Reverse Recovery Time	1 204 1//1 1004/	18	25	33	ns	
Qrr	Reverse Recovery Charge	$I_F = 30A$, $di/dt = 100A/us$	-	16	-	nC	

Notes:

- 1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature.
- 2. E_{AS} condition: Starting T_J =25°C, V_{DD} =15V, V_G =10V, R_G =25 Ω , L=0.5mH, I_{AS} =35.56A
- 3. Pulse Test: Pulse Width $\leq 300 \mu s$, Duty Cycle $\leq 0.5\%$.



TYPICAL PERFORMANCE CHARACTERISTICS



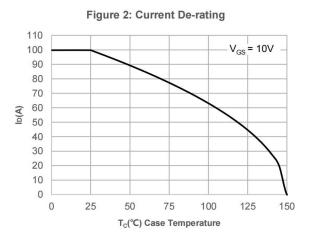
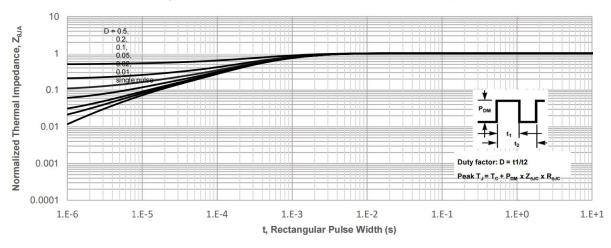
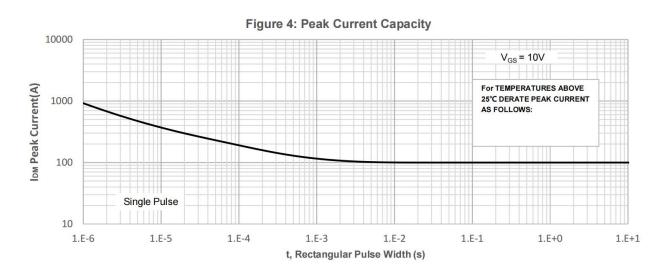


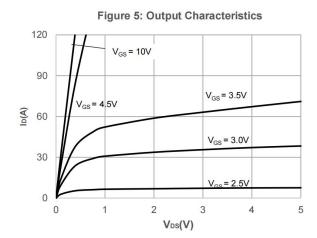
Figure 3: Normalized Maximum Transient Thermal Impedance

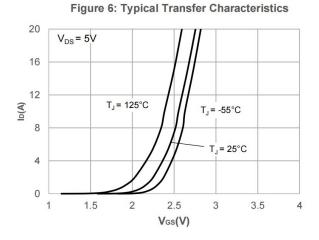


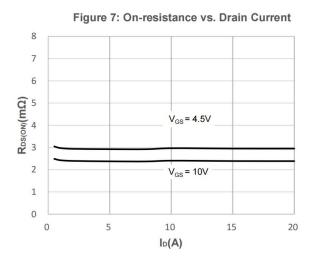


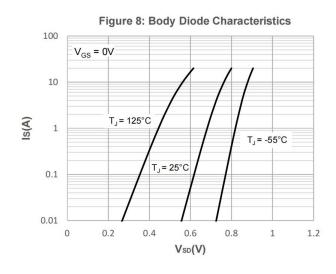


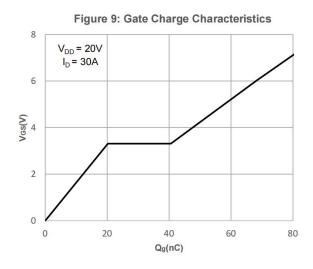
TYPICAL PERFORMANCE CHARACTERISTICS

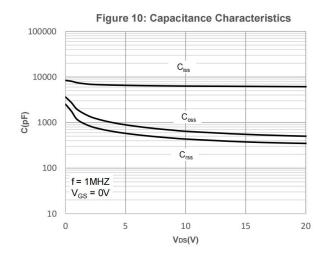














TYPICAL PERFORMANCE CHARACTERISTICS

Figure 11: Normalized Breakdown voltage vs. Junction Temperature

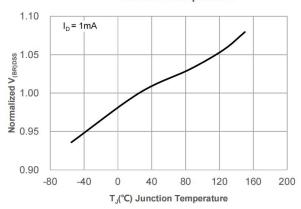


Figure 12: Normalized on Resistance vs.
Junction Temperature

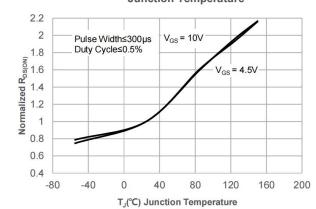
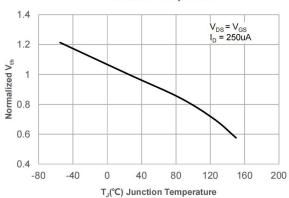


Figure 13: Normalized Threshold Voltage vs. Junction Temperature



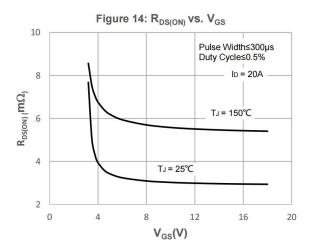
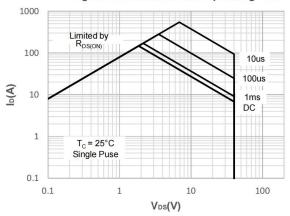


Figure 15: Maximum Safe Operating Area





TEST CIRCUIT

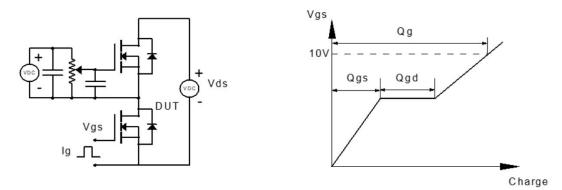


Figure 16: Gate Charge Test Circuit & Waveform

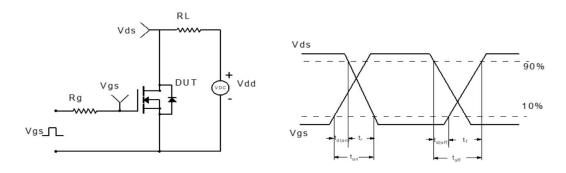


Figure 17: Resistive Switching Test Circuit & Waveform

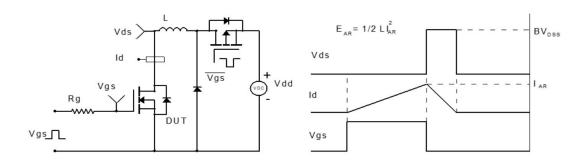


Figure 18: Unclamped Inductive Switching Test Circuit& Waveform

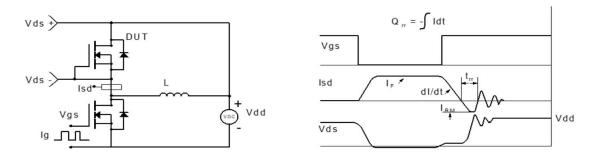
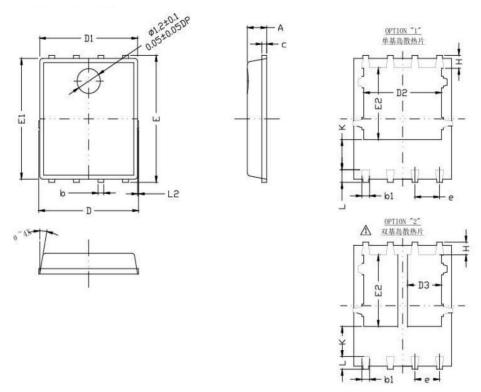


Figure 19: Diode Recovery Test Circuit & Waveform



DETAIL PACKAGE OUTLINE DRAWING (PDFN5*6-8L)



SYMBOL	MILLIMETERS			
	MIN	NOM	MAX	
A	0.90	1.00	1.10	
ь	0.25	0.30	0.35	
b1	0.30	0.40	0.45	
С	0.22	0.25	0.28	
D	-	-	5.30	
D1	4.90	5.05	5.20	
D2	4.01 REF.			
D3	1.75 REF.			
Е	6.00	6.15	6.30	
E1	5.70	5.85	6.00	
E2	3.48 REF.			
e	1.10	1.27	1.40	
Н	0.61	0.71	0.81	
K	1.10	-	-	
L	0.51	0.61	0.71	
L2	-	-	0.10	
θ	8°	-	12°	



REVISION HISTORY

Number	Description
Rev 1.0	BRT40N100P2 datasheet release